



**TEST REPORT  
FOR  
IEC 61643-1 (7.5.3)  
(SURGE IMMUNITY TEST)**

**Report No.: 11-01-MAS-055-02**

Client: JD Auspice Co., Ltd.  
Product: Surge Protective Device  
Model No.: D1-60/\*\*\*-2MV-R  
Comment Issues: N/A  
Manufacturer/supplier: JD Auspice Co., Ltd.  
Serial Voltage: 75 / 150 / 175 / 275 / 300 / 320 / 385 / 440 / 550 / 600

Date test item received: 2011/01/07  
Date test campaign completed: 2011/02/09  
Date of issue: 2011/02/09

**The test result only corresponds to the tested sample. It is not permitted to copy this report, in part or in full, without the permission of the test laboratory.**

**Total number of pages of this test report: 10 pages**

Test Engineer

*Yi-hone Cheng*

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Checked By

*Kevin Lin*

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Laboratory Introduction: Electronics Testing Center, Taiwan is recognized, filed and mutual recognition arrangement as following:

- ① ISO9001: TÜV Product Service
- ② ISO/IEC 17025: BSMI, CNLA, DGT, NVLAP, CCIBLAC, UL, Compliance
- ③ Filing: FCC, Industry Canada, VCCI
- ④ MRA: Australia, Hong Kong, New Zealand, Singapore, USA, Japan, Korea, China, APLAC through CNLA
- ⑤ FCC Registration Number: 90588, 91094, 91095

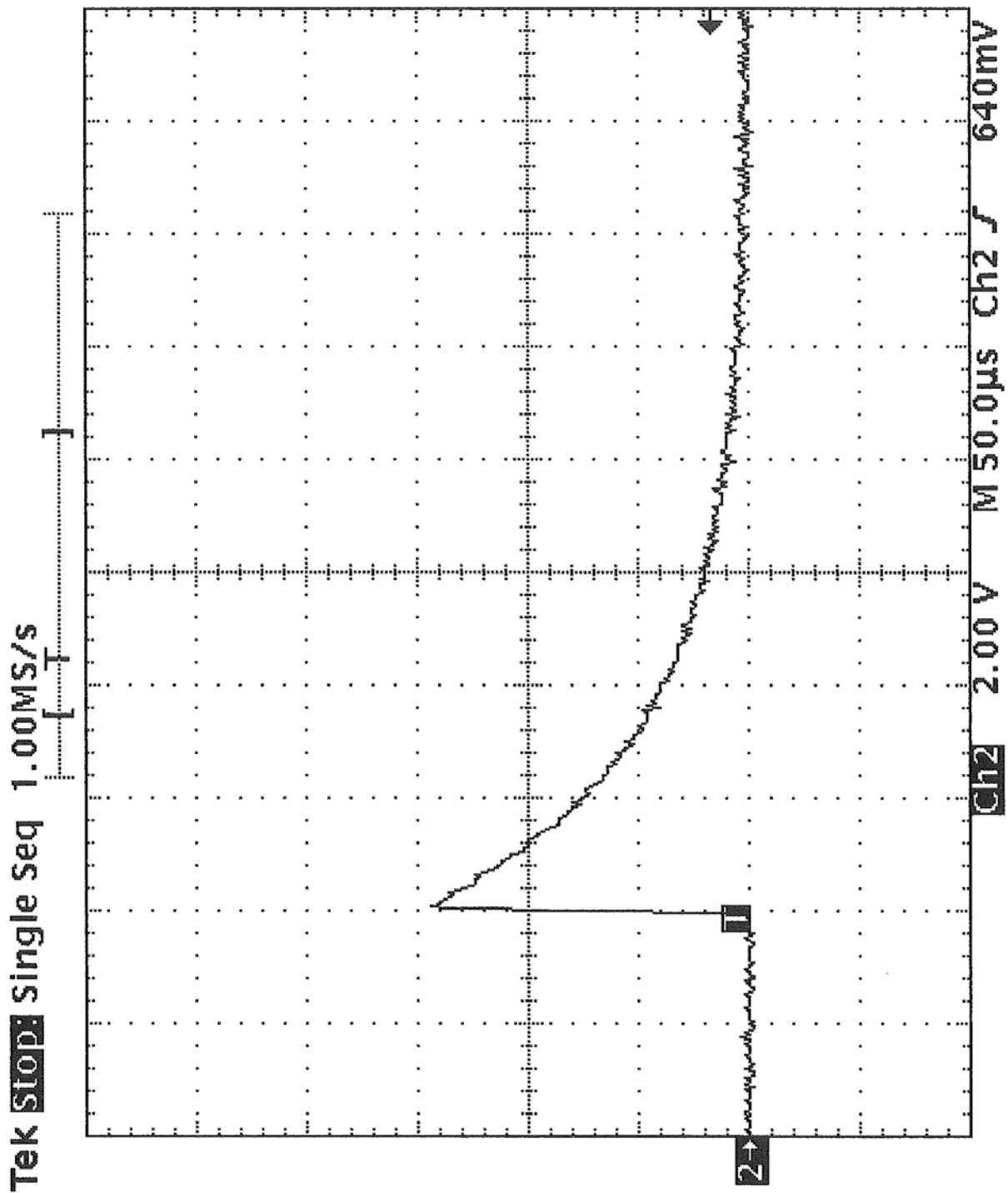
SURGE IMMUNITY TEST

Test Date: Jan. 21, 2011

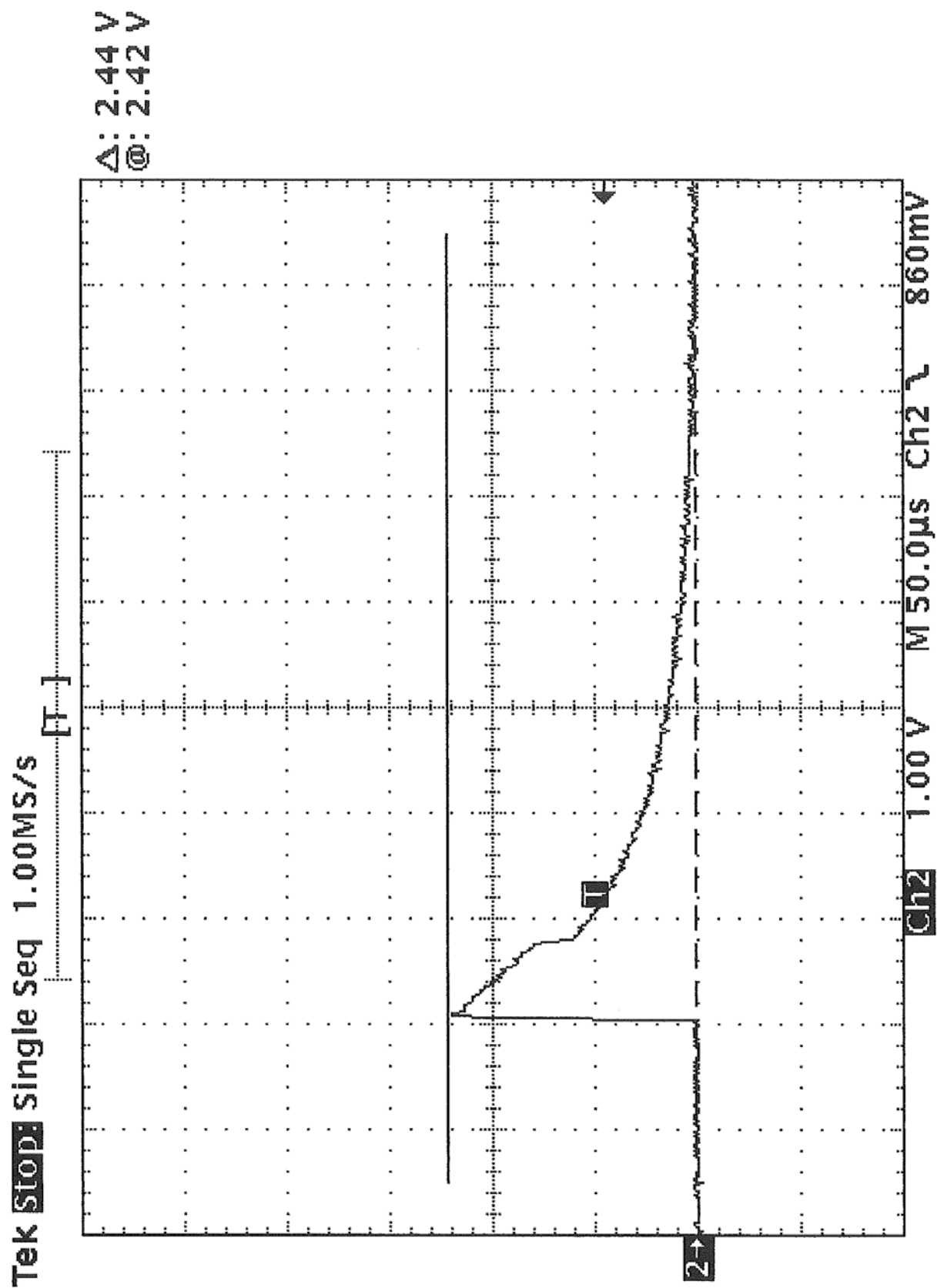
Test Specification	IEC61643-1 (7.5.3)	
Test Equipment		
Lightning Surge Simulator \ Noiseken \ LSS-15AX Voltage Probe \ Tektronix \ P6015A Oscilloscope \ Tektronix \ TDS784A		
Climatic Condition	Ambient Temperature: <u>15</u> °C                      Relative Humidity: <u>65</u> %RH	
	Atmospheric Pressure: <u>993</u> mbar	
Test Set-up	Table-top Equipment	
Operating Conditions of The Device		Static Mode

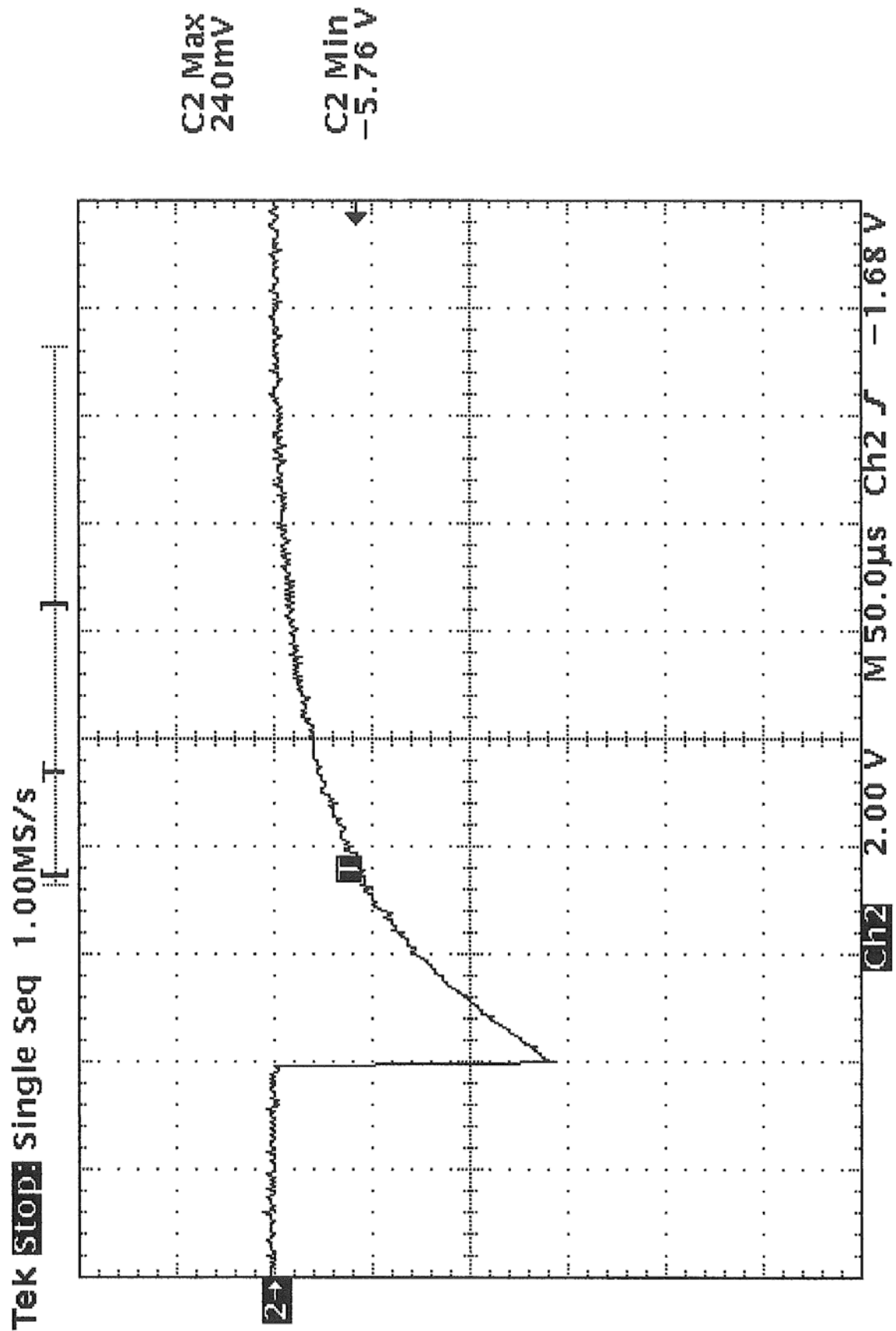
Waveform: 1.2/50 $\mu$ s(8/20 $\mu$ s)		Repetition rate: <u>60</u> sec	Times: <u>5</u> times/each condition
\Mode \Voltage \Polarity \Result		Surge HOT: Device Input	Surge COM: Device Output
6.0 kV	+	A	
	-	A	
0.9kV ~ 15.0 kV Step:10% increase	+	A	
	-	A	

Note: "A" means the EUT function was correct during the test.

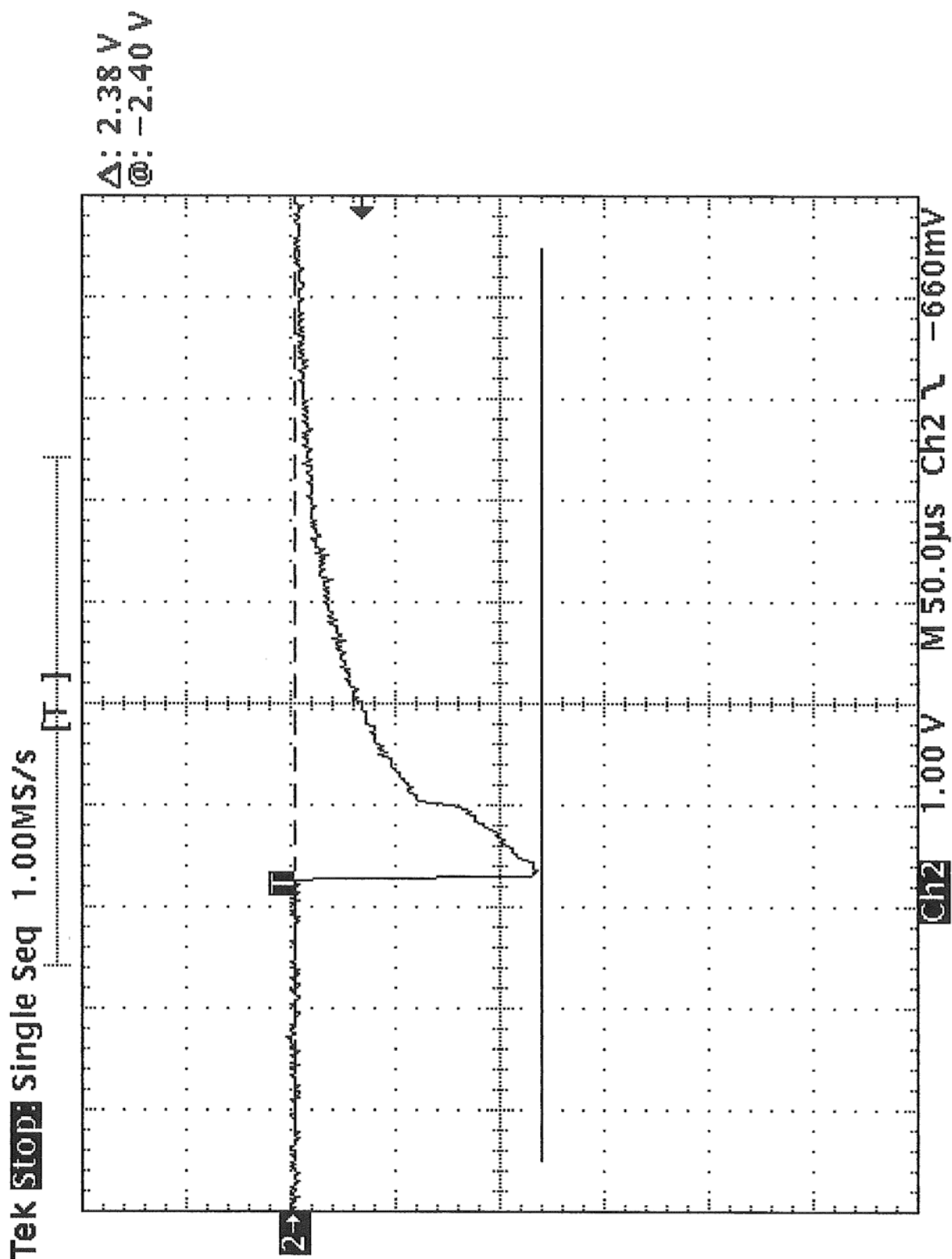
Test Voltage: +6kV Waveform (Normal)C2 Max  
5.76 VC2 Min  
-160 mV

Test Voltage: +6kV (Device Parallel)

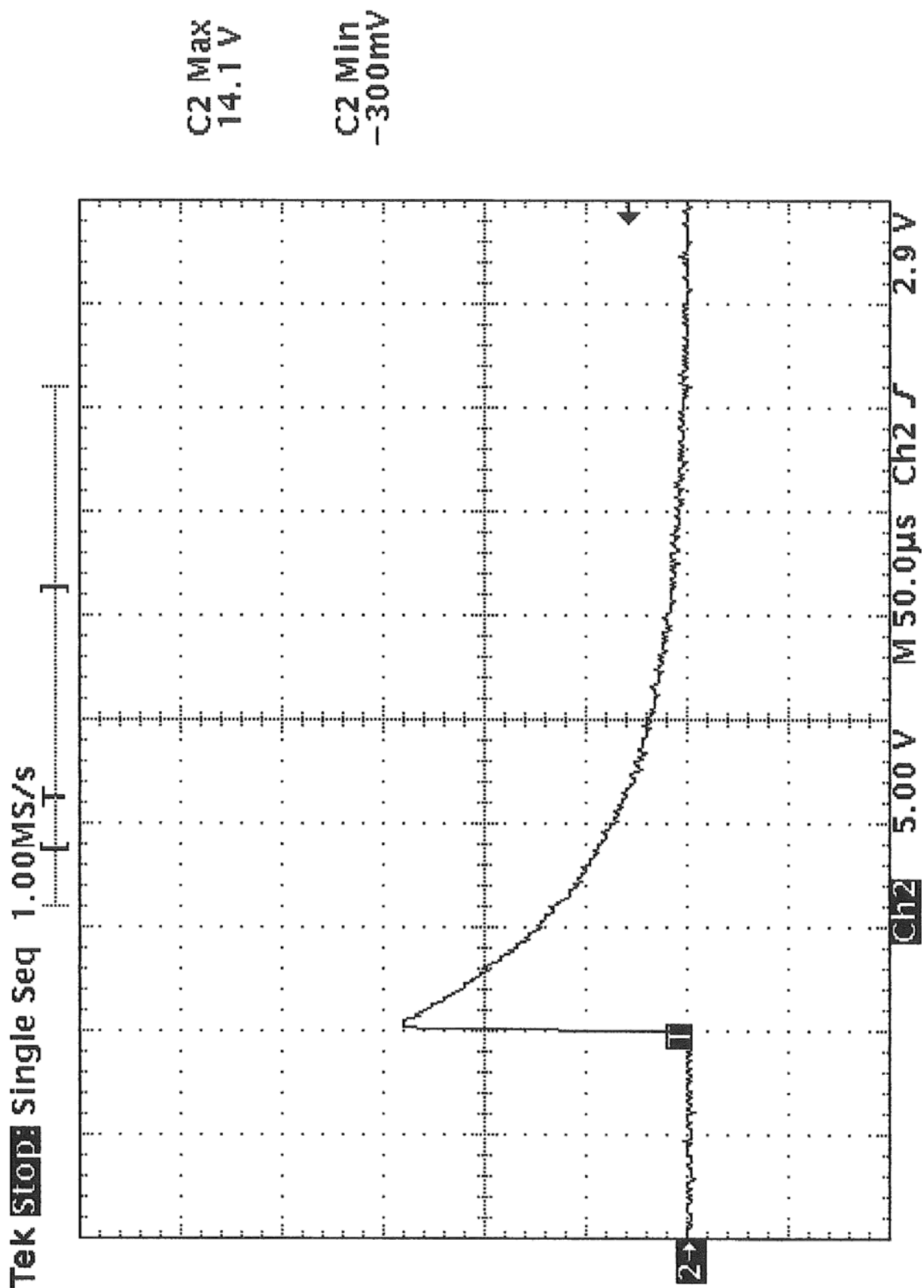


Test Voltage: -6kV Waveform (Normal)

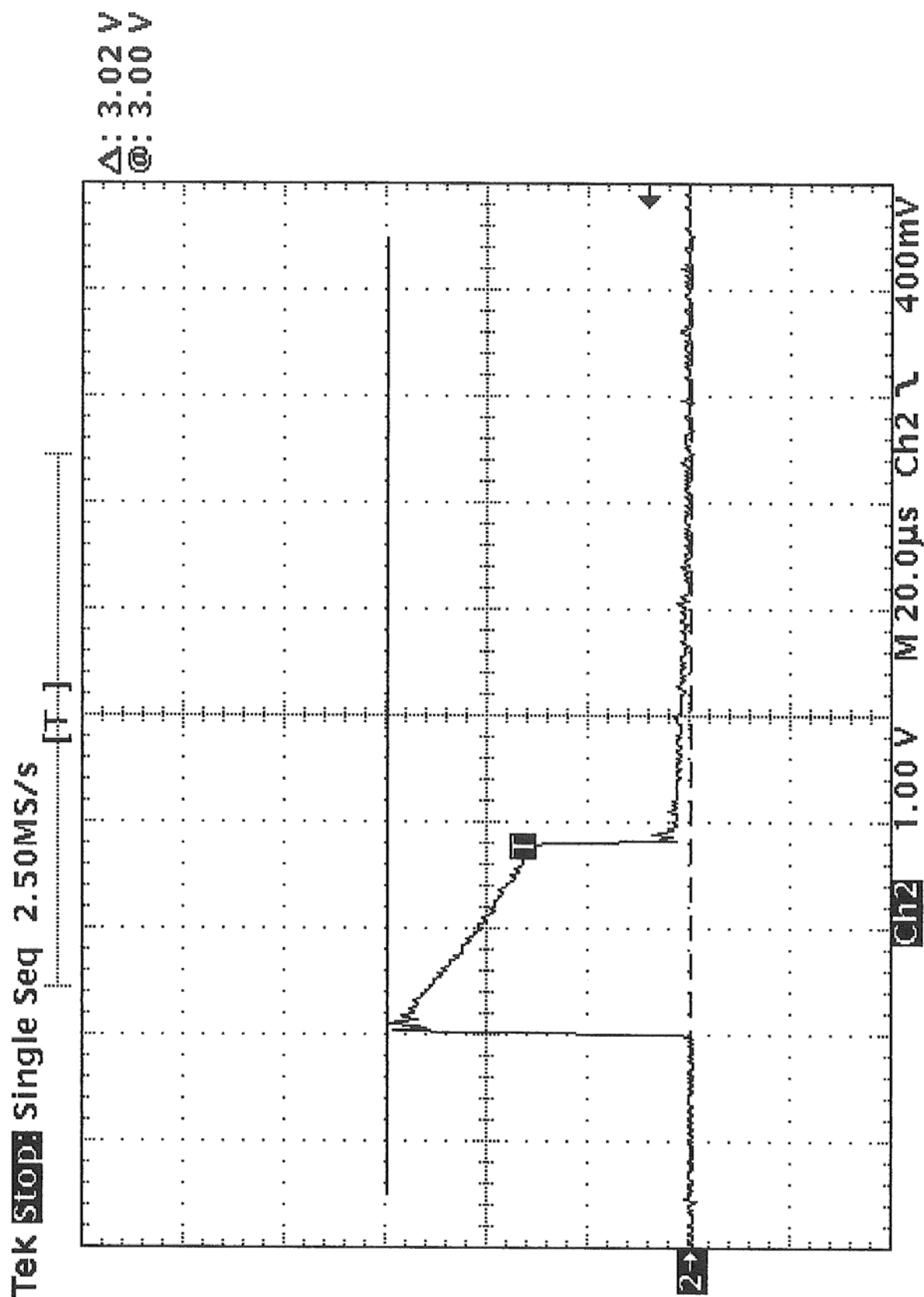
Test Voltage: -6kV (Device Parallel)



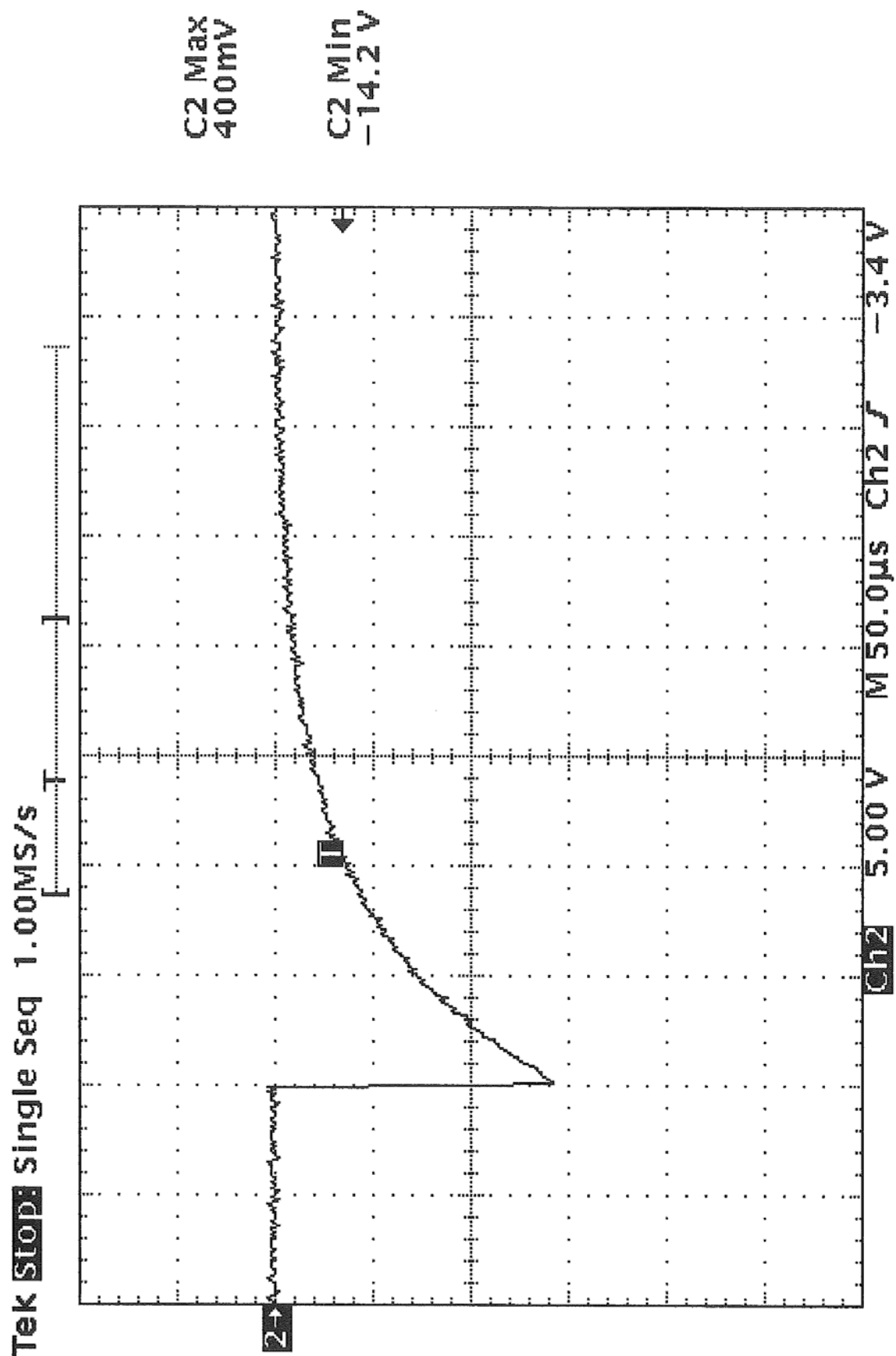
Test Voltage: +15.0 kV Waveform (Normal)



Test Voltage: +15.0 kV (Device Parallel)



Test Voltage: -15.0 kV Waveform (Normal)



Test Voltage: -15.0 kV (Device Parallel)

